## N-channel TrenchMOS intermediate level FET

Rev. 02 — 12 October 2010

**Product data sheet** 

### 1. Product profile

### 1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

### 1.2 Features and benefits

- AEC Q101 compliant
- Suitable for standard and logic level gate drive sources

### **1.3 Applications**

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

### 1.4 Quick reference data

#### Table 1. Quick reference data

- Suitable for thermally demanding environments due to 175 °C rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

	QUICK reference uata						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	40	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>	<u>[1]</u>	-	-	100	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	204	W
Static cha	racteristics						
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>		-	3.05	3.6	mΩ



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Table 1.	Quick reference data	continued				
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
Avalanch	e ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 100 \text{ A};  \text{V}_{\text{sup}} \leq 40 \text{ V}; \\ \text{R}_{\text{GS}} &= 50  \Omega;  \text{V}_{\text{GS}} = 10  \text{V}; \\ \text{T}_{j(\text{init})} &= 25 ^\circ\text{C}; \text{ unclamped} \end{split} $	-	-	368	mJ
Dynamic	characteristics					
Q <sub>GD</sub>	gate-drain charge	$I_D = 25 \text{ A}; \text{ V}_{DS} = 32 \text{ V};$ $V_{GS} = 10 \text{ V}; \text{ see } \underline{\text{Figure } 13};$ $\text{see } \underline{\text{Figure } 14}$	-	42	-	nC

[1] Continuous current is limited by package.

## 2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		2
2	D	Drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S

SOT78A (TO-220AB)

## 3. Ordering information

Table 3. Or	dering	information
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Type number	Package		
	Name	Description	Version
BUK653R4-40C	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78A

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### 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	40	V
V <sub>GS</sub>	gate-source voltage	Pulsed	<u>[1]</u>	-20	20	V
		DC	[2]	-16	16	V
I <sub>D</sub>	drain current	$T_{mb}$ = 25 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u>	[3]	-	100	А
		$T_{mb}$ = 100 °C; $V_{GS}$ = 10 V; see Figure 1	[3]	-	100	А
I <sub>DM</sub>	peak drain current	T <sub>mb</sub> = 25 °C; t <sub>p</sub> ≤ 10 μs; pulsed; see <u>Figure 3</u>		-	657	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	204	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drain	n diode					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	[3]	-	100	А
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	657	А
Avalanche r	uggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$    I_D = 100 \text{ A};  \text{V}_{\text{sup}} \leq 40 \text{ V};  \text{R}_{\text{GS}} = 50  \Omega; \\ \text{V}_{\text{GS}} = 10 \text{ V};  \text{T}_{j(\text{init})} = 25 ^{\circ}\text{C}; \text{ unclamped} $		-	368	mJ
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy		[4][5][6]	-	-	J

[1] Accumulated pulse duration not to exceed 5mins.

[2] -16V accumulated duration not to exceed 168 hrs.

[3] Continuous current is limited by package.

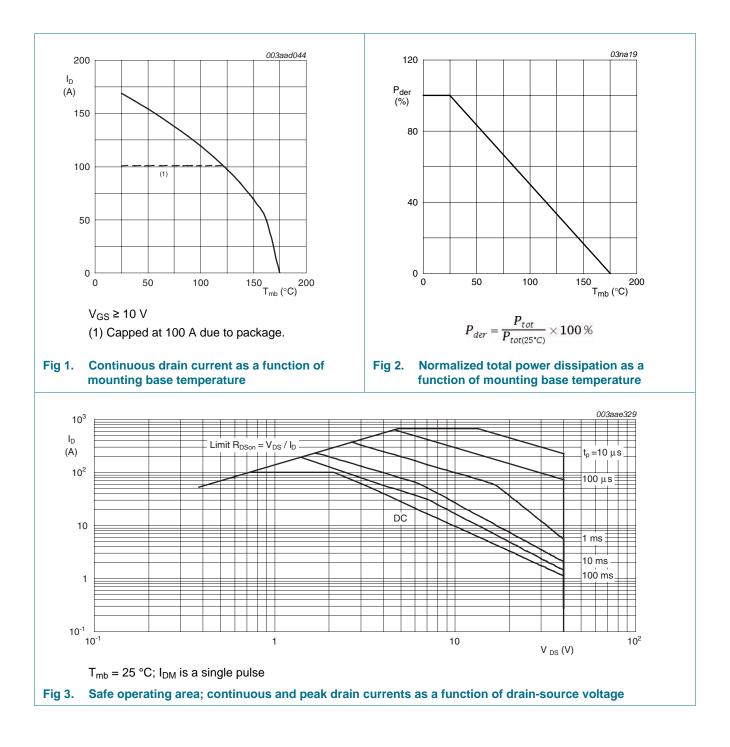
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[6] Refer to application note AN10273 for further information.

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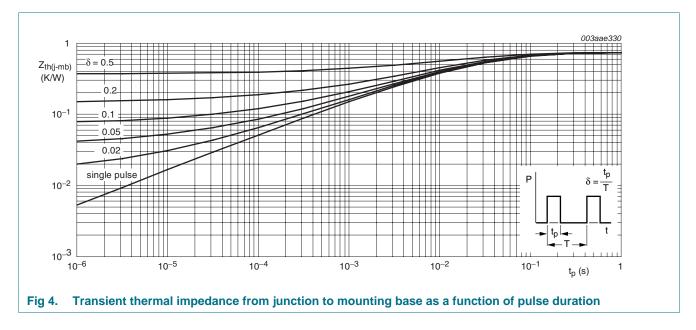
#### N-channel TrenchMOS intermediate level FET



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## 5. Thermal characteristics

	Thermal endlaetensties					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 4	-	-	0.74	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W



#### Table 5. Thermal characteristics

### N-channel TrenchMOS intermediate level FET

## 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V <sub>(BR)DSS</sub>		$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	40	-	-	V
	voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	36	-	-	V
V <sub>GS(th)</sub>	V <sub>GS(th)</sub> gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	1.8	2.3	2.8	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see <u>Figure 10</u>	-	-	3.3	V
		$I_D = 2.5 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see <u>Figure 10</u>	0.8	-	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS}$ = 40 V; $V_{GS}$ = 0 V; $T_j$ = 175 °C	-	-	500	μA
		$V_{DS}$ = 40 V; $V_{GS}$ = 0 V; $T_j$ = 25 °C	-	0.02	1	μA
I <sub>GSS</sub>	gate leakage current	$V_{DS}$ = 0 V; $V_{GS}$ = 20 V; $T_j$ = 25 °C	-	2	100	nA
		$V_{DS}$ = 0 V; $V_{GS}$ = -20 V; $T_j$ = 25 °C	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	3.05	3.6	mΩ
		V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	4.2	5.3	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	4.5	6	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 °C; see <u>Figure 12</u> ; see <u>Figure 11</u>	-	-	7.6	mΩ
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	125	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 5 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	71	-	nC
Q <sub>GS</sub>	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	23	-	nC
Q <sub>GD</sub>	gate-drain charge	see <u>Figure 13;</u> see <u>Figure 14</u>	-	42	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	6016	8020	pF
C <sub>oss</sub>	output capacitance	$T_j = 25 \text{ °C}; \text{ see } Figure 15$	-	739	870	pF
C <sub>rss</sub>	reverse transfer capacitance		-	510	700	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	40	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \ \Omega$	-	87	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	224	-	ns
t <sub>f</sub>	fall time		-	117	-	ns
L <sub>D</sub>	internal drain inductance	from drain lead 6 mm from package to centre of die ; $T_j = 25 \text{ °C}$	-	4.5	-	nH
L <sub>S</sub>	internal source inductance	from source lead to source bond pad ; T <sub>j</sub> = 25 °C	-	7.5	-	nH

Characteristics ... continued

Parameter

Table 6.

Symbol

# BUK653R4-40C

Max

Unit

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Тур

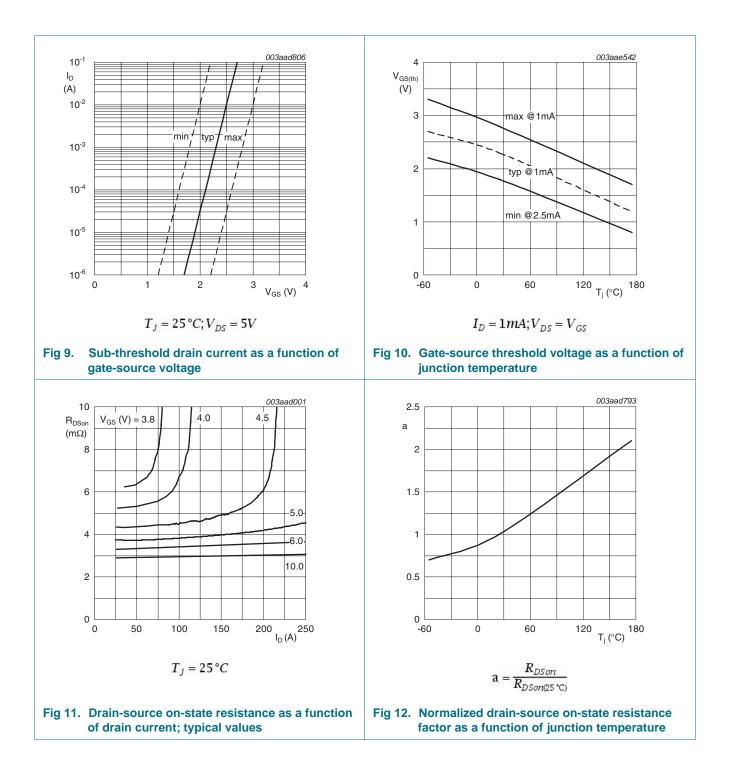
Min

	n diode						
urce-drai	ii aloao						
D	source-drain voltage	I <sub>S</sub> = 25 A; V <sub>C</sub> see <mark>Figure 1</mark>	<sub>3S</sub> = 0 V; T <sub>j</sub> = 25 °C; <u>6</u>	-	0.8	1.2	V
	reverse recovery time	I <sub>S</sub> = 20 A; dI <sub>S</sub>	<sub>S</sub> /dt = -100 A/µs;	-	48	-	ns
	recovered charge	V <sub>GS</sub> = 0 V; V	<sub>DS</sub> = 25 V	-	82	-	nC
150 🖵		003aae331	12			003aae334	
g <sub>fs</sub>			R <sub>DSon</sub>				
(S)			(mΩ) 10				
120							
			8				
90			0				
			6				
60							
			4				
30							
			2				
T							
0 L			0				
0	$T_j = 25$ °C; $V_{DS} = 25$		0 <i>T</i> ,	$^{5}$ = 25 °C; $I_{D}$ ce on-state	a = 25 A	<sup>15</sup> (V) <sup>15</sup> <b>ce as a fi</b>	unctic
0 ig 5. Foi		I <sub>D</sub> (A)	0	; = 25 °C; I <sub>D</sub> :e on-state ∣	V <sub>G</sub> ) = 25 A resistanc	<sub>is (V)</sub> ce as a fi	unctic
o ig 5. Foi dra	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A)	0 Tj Fig 6. Drain-sourc of gate-sour	; = 25 °C; I <sub>D</sub> :e on-state ∣	v <sub>G</sub> = 25 A resistanc ; typical y	<sub>is (V)</sub> ce as a fi	unctic
0 ig 5. For dra 100	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A) V s a function of	0 Tj Fig 6. Drain-sourc of gate-source 250	$r = 25 \text{ °C}; I_D$ the on-state price voltage	v <sub>G</sub> = 25 A resistanc ; typical y	es (V) ce as a fu values	unctic
o ig 5. Foi dra	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A) V s a function of	0 Tj Fig 6. Drain-sourc of gate-sour	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	<sub>is (V)</sub> ce as a fi values	unctic
0 ig 5. For dra 100 ID	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A) V s a function of	0 <i>T</i> J Fig 6. Drain-source of gate-source ID V <sub>GS</sub> (V) = 10	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	es (V) ce as a fu values	unctic
0 ig 5. For dra 100 I <sub>D</sub> (A)	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A) V s a function of	$T_{J}$ Fig 6. Drain-source of gate-source $I_{D}$ (A)	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	es (V) ce as a fu values	unctic
0 ig 5. For dra 100 I <sub>D</sub> (A)	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A) V s a function of	$T_{J}$ Fig 6. Drain-source of gate-source $I_{D}$ (A)	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	es (V) ce as a fu values	unctic
0 ig 5. For dra	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A) V s a function of	$T_{J}$ Fig 6. Drain-source of gate-source of gate	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	(V) ce as a fu values 003aad002 4.5	unctic
0 ig 5. For dra 100 ID (A) 80 60	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A) V s a function of	$T_{J}$ Fig 6. Drain-source of gate-source of gate	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	es (V) ce as a fu values	unctic
0 ig 5. For dra	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A) V s a function of	$T_{J}$ Fig 6. Drain-source of gate-source of gate	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	(V) ce as a fu values 003aad002 4.5	unctic
0 ig 5. For dra 100 ID (A) 80 60	$T_j = 25 \text{ °C}; V_{DS} = 25$ rward transconductance a a in current; typical values	I <sub>D</sub> (A) V s a function of	$T_{J}$ Fig 6. Drain-source of gate-source of gate	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	Se as a function of the second sec	unctic
0 ig 5. For dra 100 ID (A) 80 60	$T_j = 25$ °C; $V_{DS} = 25$ rward transconductance a	I <sub>D</sub> (A) V s a function of	$T_{J}$ Fig 6. Drain-source of gate-source of gate	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	2003aad002 4.5 4.0 3.8 3.6	unctic
0 ig 5. For dra 100 (A) 80 60 40	$T_j = 25 \text{ °C}; V_{DS} = 25$ rward transconductance a a in current; typical values	I <sub>D</sub> (A) V s a function of	$T_{J}$ Fig 6. Drain-source of gate-source of gate	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	Se as a function of the second sec	unctio
0 ig 5. For dra 100 (A) 80 60 40 20	$T_j = 25 \text{ °C}; V_{DS} = 25$ rward transconductance a a in current; typical values	I <sub>D</sub> (A) V s a function of	$T_{J}$ Fig 6. Drain-source of gate-source of gate	$r = 25 \text{ °C}; I_D$ the on-state price voltage	V <sub>G</sub> = 25 A resistanc ; typical	2003aad002 4.5 4.0 3.8 3.6	unctio
0 ig 5. For dra 100 (A) 80 60 40	$T_j = 25 \text{ °C}; V_{DS} = 25$ rward transconductance a an current; typical values $T_j = 175 \text{ °C}$ $T_j = 25$	I <sub>D</sub> (A) V s a function of 003aae333	$T_{J}$ Fig 6. Drain-source of gate-source of gate	e 25 °C; I <sub>D</sub> rce voltage	$v_{G}$ = 25 A resistance ; typical y	e as a fu values	unctio
0 ig 5. For dra 100 (A) 80 60 40 20 0	$T_j = 25 \text{ °C}; V_{DS} = 25$ ward transconductance a bin current; typical values $T_j = 175 \text{ °C}$ $T_j = 25$ $T_j = 175 \text{ °C}$ $T_j = 25$	I <sub>D</sub> (A) V s a function of 003aae333	$ \begin{array}{c}                                     $	$r = 25 \text{ °C}; I_D$ e on-state provide the state of the	$v_{G}$ p = 25  A resistance 5.0 5.0 1.5	S (V) S	unctio
0 ig 5. For dra 100 (A) 80 60 40 20 0	$T_j = 25 \text{ °C}; V_{DS} = 25$ rward transconductance a an current; typical values $T_j = 175 \text{ °C}$ $T_j = 25$	I <sub>D</sub> (A) V s a function of 003aae333	$ \begin{array}{c}                                     $	e 25 °C; I <sub>D</sub> rce voltage	$v_{G}$ p = 25  A resistance 5.0 5.0 1.5	e as a fu values	unctio
0 ig 5. For ID (A) 80 60 40 20 0 0	$T_j = 25 \text{ °C}; V_{DS} = 25$ ward transconductance a bin current; typical values $T_j = 175 \text{ °C}$ $T_j = 25$ $T_j = 175 \text{ °C}$ $T_j = 25$	I <sub>D</sub> (A) V s a function of 003aae333 0003aae333 0003aae333 0003aae333 0003aae333 0003aae3 0003aae333 0003aae333 0003aae333 0003aae333 0003aae333 0003aae333 0003aae333 0003aae333 0003aae333 0003aae333 0003aae333 0003aae33 0003aae33 0003aae33 0003aae33 0003aae33 0003aae33 0003aae33 0003aae33 0003aae33 0003aae33 0003aae3 0003aae3 0003aae3 0003aae3 0003aae3 0003aae3 0003aae3 0003aae3 0003aae3 0000 0003aae3 0000 0000	$ \begin{array}{c}                                     $	$f = 25 \text{ °C}; I_D$ rece voltage: f = 6.0 f = 0 f = 0	$v_{G}$ p = 25  A resistance 5.0 5.0 1.5	Ce as a fu values 003aad002 4.5 4.0 4.0 3.8 3.6 3.6 3.4 	

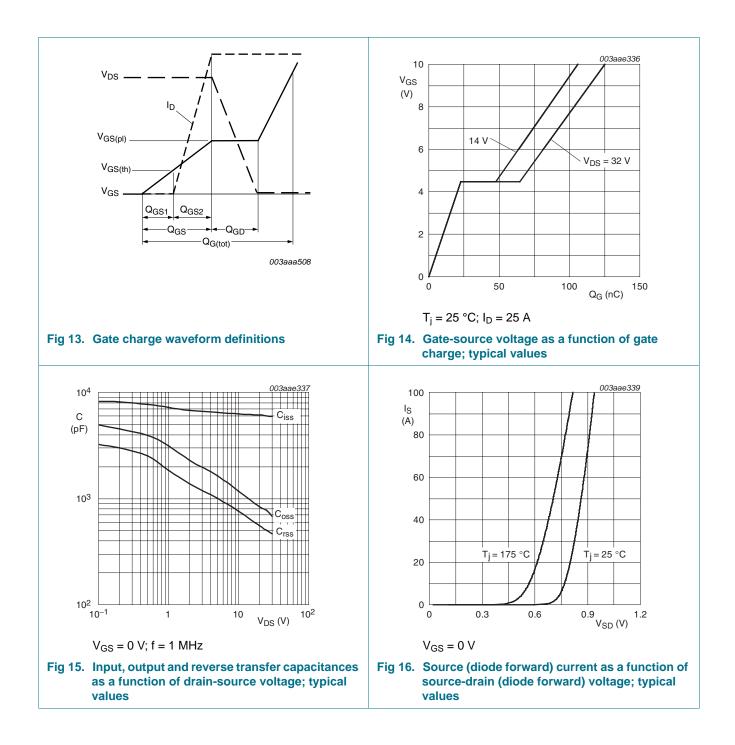
Conditions

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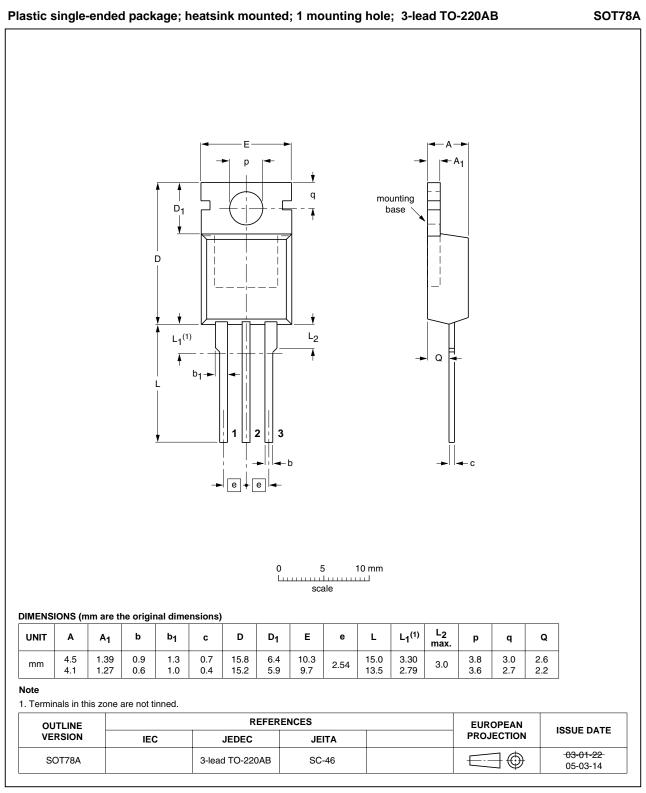
#### N-channel TrenchMOS intermediate level FET



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### 7. Package outline



#### Fig 17. Package outline SOT78A (TO-220AB)

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## 8. Revision history

Table 7. Revision I	nistory			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK653R4-40C v.2	20101012	Product data sheet	-	BUK653R4-40C v.1
Modifications:	<ul> <li>Status change</li> </ul>	d from objective to product.		
	<ul> <li>Various chang</li> </ul>	es to content.		
BUK653R4-40C v.1	20100520	Objective data sheet	-	-

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### 9. Legal information

#### 9.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <u>http://www.nxp.com</u>.

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Date of release: 12 October 2010 Document identifier: BUK653R4-40C